

V PACKAGE N8T25 0°C TO +75°C

DIGITAL 8000 SERIES TTL/MSI

## DESCRIPTION

The 8T25 is a Dual MOS-to-TTL Sense Amplifier designed to accept low level MOS signals from the output of Random Access Memories and store the information in a latch in response to an external Strobe signal. A tristate buffer presents the data to the output using conventional TTL logic levels. The 8T25 operates from a single +5 volt supply.

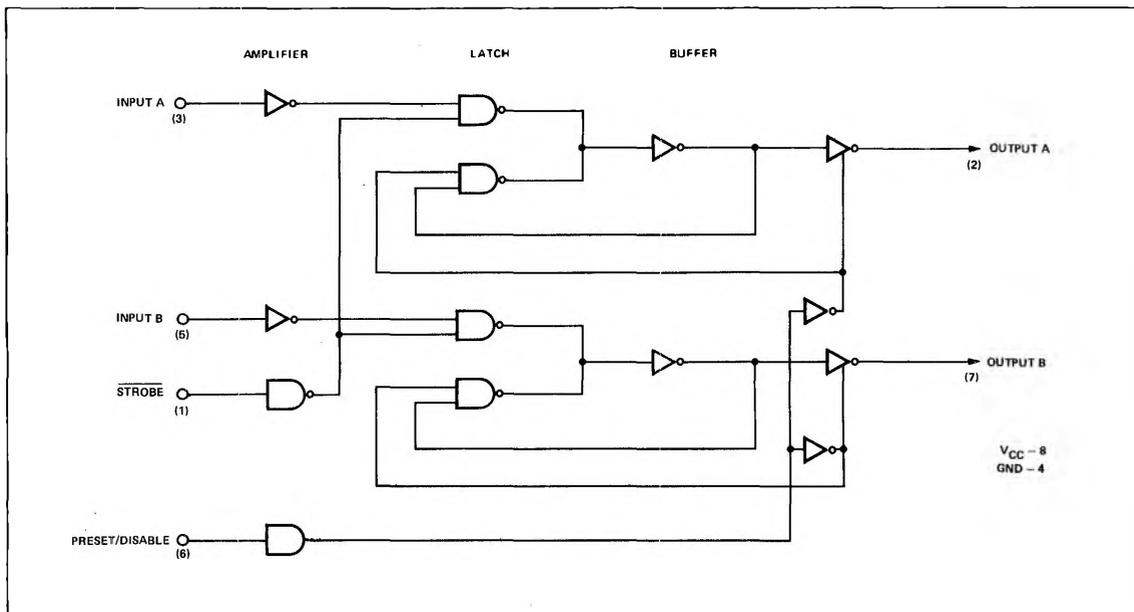
## CIRCUIT OPERATION

A logic "1" level on the Disable line will effectively disconnect the outputs of the Sense Amplifier from a common bus by turning both totem-pole transistors off. When the Disable line returns to a logic "0" level, the outputs will be preset to a logic "1" state. A low-going Strobe pulse will then transfer the data at Inputs A and B to their respective outputs non-inverted.

Due to the internal latch, output data will remain stable regardless of any change in input levels until a Disable signal again forces both outputs to the high impedance state.

The data inputs are current sensitive with a threshold of  $300\mu\text{A}$ , although the driving source voltage must be greater than 1.6 volts in the high level.

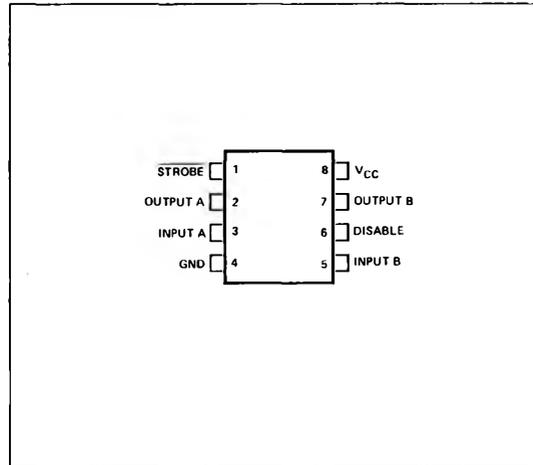
## LOGIC DIAGRAM



## FEATURES

- MOS-TO-TTL CONVERTER
- INTERNAL LATCH
- TRISTATE OUTPUTS
- SINGLE +5V SUPPLY

## PIN CONFIGURATION



ELECTRICAL CHARACTERISTICS ( $T_A = 0^\circ\text{C}$  TO  $75^\circ\text{C}$ ,  $V_{CC} = 5\text{V} \pm 5\%$ )

PARAMETER	LIMITS				INPUTS					
	MIN.	TYP.	MAX.	UNITS	A	B	DISABLE	STROBE	OUTPUTS	NOTES
"1" Output Voltage	2.8	3.5		V	400 $\mu\text{A}$	400 $\mu\text{A}$	0.8V	0.8V	-1.5mA	7
"0" Output Voltage			0.40	V	200 $\mu\text{A}$	200 $\mu\text{A}$	0.8V	0.8V	16mA	8
Output "1" Leakage Current Output "A"			100	$\mu\text{A}$	200 $\mu\text{A}$	1.5mA	2.0V	0.8V	3.9V	
Output "B"			100	$\mu\text{A}$	1.5mA	200 $\mu\text{A}$	2.0V	0.8V	3.9V	
Output "0" Leakage Current			100	$\mu\text{A}$	1.5mA	1.5mA	2.0V	0.8V	0V	
Input Clamp Voltage			-1.5	V			-12mA	-12mA		
Power/Current Consumption			210/40	mW/mA	400 $\mu\text{A}$	400 $\mu\text{A}$	4.5V	0V		11
"0" Input Current (Strobe, Disable)	-0.1		-1.6	mA			0V	0V		
"1" Input Current (Strobe, Disable)			40	$\mu\text{A}$			4.5V	4.5V		
Input Voltage Rating (Strobe, Disable)			5.5	V			1.0mA	1.0mA		
Output Short Circuit Current	-20		-70	mA				2.0V	0V	10, 11

## NOTES:

- All voltage measurements are referenced to the ground terminal. Terminals not specifically referenced are left electrically open.
- All measurements are taken with ground pin tied to zero volts.
- Positive current flow is defined as into the terminal referenced.
- Positive logic: "UP" Level = "1", "DOWN" Level = "0".
- Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the isolation diodes become forward biased.
- Output source current is supplied through a resistor to ground.
- Output sink current is supplied through a resistor to  $V_{CC}$ .
- Refer to AC Test Figure.
- Not more than one output should be shorted at a time.
- $V_{CC} = 5.25\text{V}$ .

ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ ,  $V_{CC} = 5.0\text{V}$ )

PARAMETER	LIMITS				INPUTS					
	MIN.	TYP.	MAX.	UNITS	A	B	DISABLE	STROBE	OUTPUTS	NOTES
Propagation Delay Strobe to Output ( $t_{ds}$ )		15	25	ns						Fig. 1
Disable to "0" Output ( $t_{pZL}$ )		15	25	ns						Fig. 2
"0" Output to Disable ( $t_{pLZ}$ )		8	15	ns						Fig. 2
Disable to "1" Output ( $t_{pZH}$ )		15	25	ns						Fig. 3
"1" Output to Disable ( $t_{pHZ}$ )		9	20	ns						Fig. 3

AC TEST CIRCUITS AND WAVEFORMS

PROPAGATION DELAY (STROBE TO OUTPUT)

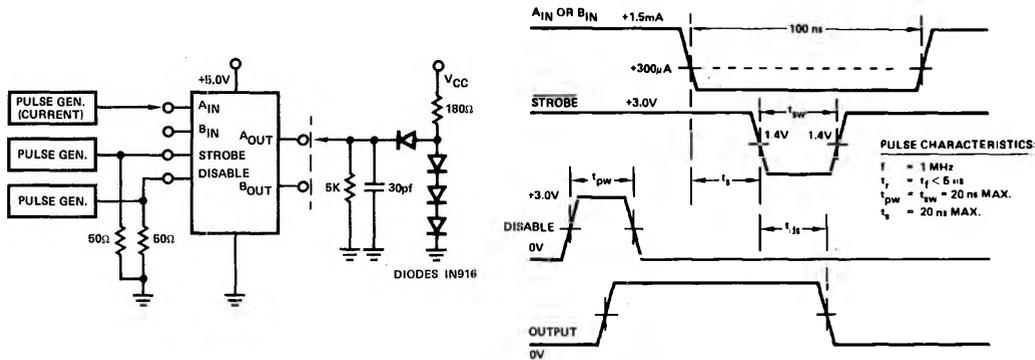
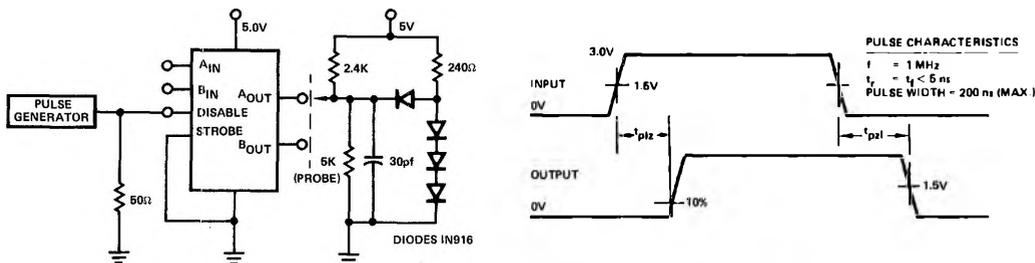


Fig. 1

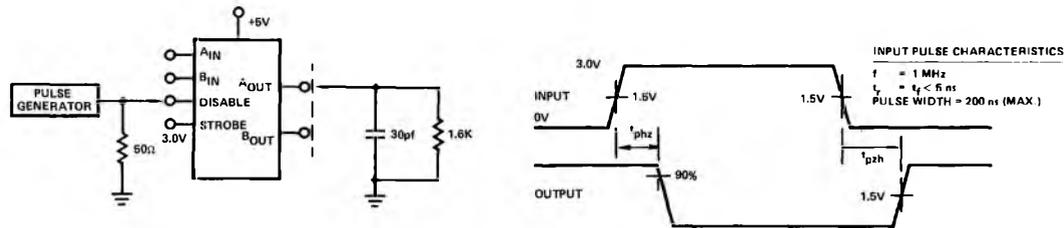
PROPAGATION DELAY (DISABLE TO OUTPUT)



NOTE: t<sub>p1z</sub> = "0" OUTPUT TO HIGH-Z  
t<sub>pz1</sub> = HIGH-Z TO "0" OUTPUT

Fig. 2

PROPAGATION DELAY (DISABLE TO OUTPUT)



NOTE: t<sub>p1z</sub> = "1" OUTPUT TO HIGH-Z  
t<sub>pz1</sub> = HIGH-Z TO "0" OUTPUT

Fig. 3

TYPICAL APPLICATION

